

N -Channel 100-V (D-S) MOSFET

Description

The device is the highest performance trench N-ch MOSFET with extreme high cell density, which provide excellent $R_{DS(ON)}$ and gate charge for most of the synchronous buck converter applications.

The device meets the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

Features

- Max Ron@Vgs 10V=1.9mΩ
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

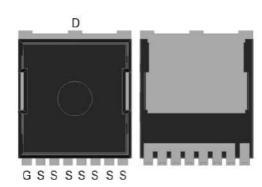
Typical Applications

- Power Tools
- Motor Control Applications
- UPS
- Synchronous Rectification in SMPS

Package type: TOLL

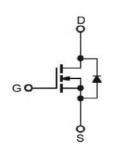
Packing & Order Information

2,000/Reel

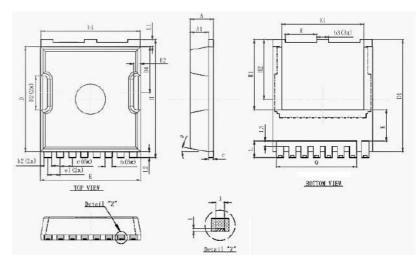


RoHS Compliant

Graphic Symbol

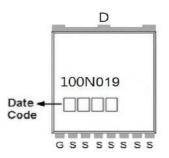


Package Dimension



SYMBOL	MILLIMETER			SYMBOL.	MILLIMETER				
	MIN.	NOM.	MAX.	SIMBOL.	MIN.	NOM.	MAX.		
Α	2.200	2.300	2.400	el	1. 225 BSC				
Al	1.700	1.800	1.900	Н	11.600 11.700 11.80				
ь	0.600	0.700	0.800	H1	6.950 BSC				
ь1	9.700	9.800	9.900	H2	5. 900 BSC				
b2	0.650	0.750	0.850	i	0. 100 REF.				
b3	1.100	1.200	1.300	j	0.350 REF.				
С	0.400	0.500	0.600	К	3. 100 REF.				
D	10. 300	10.400	10, 500	L	1.550 1.650 1.750				
D1	11.000	11.100	11. 200	L.1	0.600	0.700	0.800		
D2	3. 200	3. 300	3.400	L2	0.500	0.600	0.700		
D4	4. 470	4.570	4.670	L3	0.400	0.500	0.600		
E	9.800	9.900	10.000	Q	7. 950 REF.				
E1	8.000	8.100	8. 200	R	3.000	3.100	3, 200		
E2	0.500	0.600	0.700	0	10° REF.				
е		1, 200 BSC							

Marking





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MAXIMUM RATINGS AND ELECTRICAL CHARACTERISTICS

Absolute Maximum Ratings					
Symbol	Parameter	Value	Units		
V _{DS}	Drain-Source Voltage	100	V		
V _G s	Gate-Source Voltage	±20	V		
lo	Continuous Drain Current¹ (T _C =25°C)	330	Α		
	Continuous Drain Current¹ (Tc=100°C)	225	Α		
I _{DM}	Pulsed Drain Current ^{1,2}	1000	Α		
las	Single Pulse Avalanche Current, L =1.0mH ³	40	Α		
Eas	Single Pulse Avalanche Energy, L =1.0mH³	800	mJ		
PD	Power Dissipation ⁴ (T _C =25°C)	333	W		
T _J /T _{STG}	Operating Junction and Storage Temperature	-55 to +175	°C		

Thermal Resistance Ratings						
Symbol	Parameter	Maximum	Units			
$R_{\theta JA}$	Maximum Junction-to-Ambient ¹	40	°C/W			
R _{0JC}	Maximum Junction-to-Case ¹	0.45	°C/W			

Electrical Characteristics (T _J =25°C unless otherwise specified)						
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
V _{GS (th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	2.0	-	4.0	V
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250µA	100	-	-	V
g fs	Forward Transconductance	V _{DS} =5V, I _D =20A	-	75	-	S
I _{GSS}	Gate-Source Leakage Current	V _{DS} =0V, V _{GS} =±20V	_	_	±100	nA
I _{DSS}	Drain-Source Leakage Current	V _{DS} =80V, V _{GS} =0V, T _J =25°C V _{DS} =80V, V _{GS} =0V, T _J =100°C	-	-	1 100	μА
R _{DS (on)}	Static Drain-Source On-Resistance ²	V _{GS} =10V, I _D =90A	_	1.6	1.9	mΩ
EAS	Single Pulse Avalanche Energy ⁵	V _{DD} =50V, L =1mH, I _{AS} =30A	450	-	-	mJ
V _{SD}	Diode Forward Voltage ²	I _S =1A, V _{GS} =0V, T _J =25°C	-	-	1.2	V
Is	Continuous Source Current ^{1,6}	V _G =V _D =0V, Force Current	-	-	100	Α



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Dynamic	:					
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Qg	Total Gate Charge ²	V _{DS} =50V		212		
Qgs	Gate-Source Charge	I _D =90A		59		nC
Qgd	Gate-Drain ("Miller") Charge	V _{GS} =10V		53		
td(on)	Turn-On Delay Time ²	V _{DS} =50V		47		
tr	Rise Time	I _D =20A		28		
td(off)	Turn-Off Delay Time	V _{GS} =10V		79		ns
tf	Fall Time	$R_G = 3\Omega$		18		
Ciss	Input Capacitance	V _{DS} =50V		13362		
Coss	Output Capacitance	V _{GS} =0V		1917		pF
Crss	Reverse Transfer Capacitance	f=1.0MHz		386		1
Rg	Gate Resistance	V _{GS} =V _{DS} =0V, f =1.0MHz		1.0		Ω

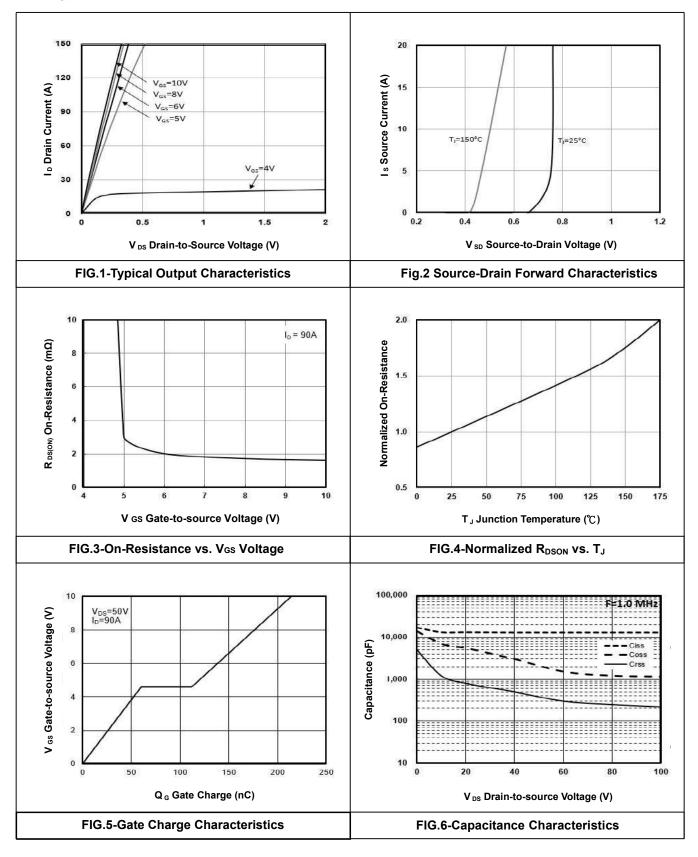
Notes

- 1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2. The data tested by pulsed, pulse width \leq 300us, duty cycle \leq 2%.
- 3. The EAS data shows maximum rating. The test condition is V_{DD} =50V, V_{GS} =10V, L=1.0mH, I_{AS} =40A.
- 5. The Min. value is 100% EAS tested guarantee.
- 6. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.



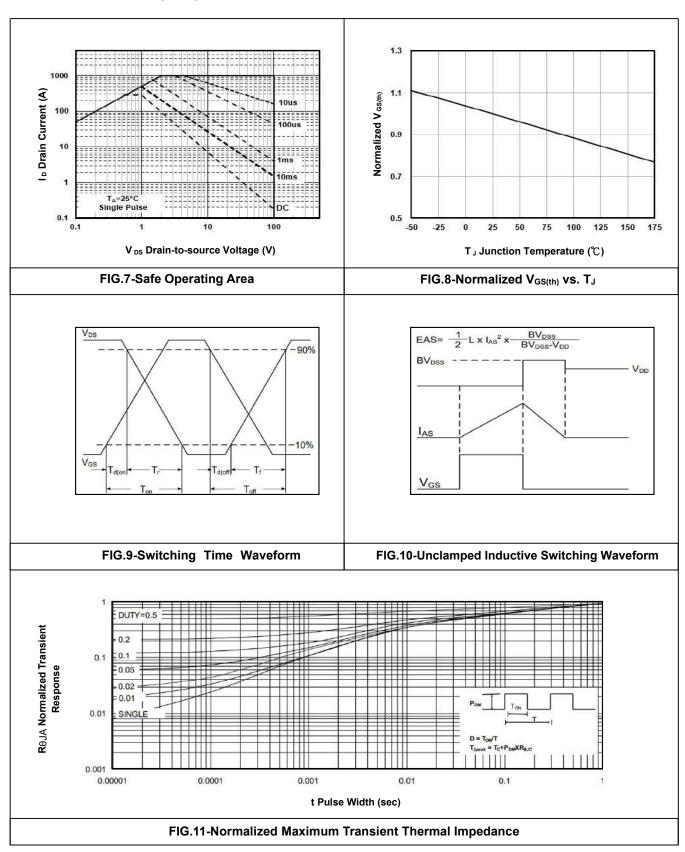
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• Typical Electrical Characteristics





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